IEEE 802.3ck Input Referred Noise Consideration

Eta_0 is a differential noise term used to set the "Input Referred Noise floor"

 The Instrumentation version of this is it's intrinsic differential noise floor. The need to raise the input referred noise floor to the "eta_0" level as a pre-requisite to performing VEC calculations, suggests the instruments noise floor is below that of eta_0 to begin with.

X	a0.xlsx
2608 -	<pre>H_ctf2=H_low2.*ctle_gain2;</pre>
2609 -	end
2610	
2611	<pre>%% Equation 93A-35 - independent of FFE setting %%</pre>
2612 -	sigma_N = sqrt(param.eta_0*sum(abs(H_sy(2:end) .* H_r(2:end) .* H_ctf(2:end)).^2 .* diff(chdata(1).faxis)/1e9));
2613 -	<pre>sigma_N1= sigma_N;</pre>
2614 -	if OP.RX_CALIBRATION
2615 -	<pre>sigma_ne = get_sigma_noise(H_ctf2, param, chdata, sigma_bn); %% Equation 93A-48 %%</pre>
2616 -	sigma NEXT=0;
2617 -	else

 The proposed level for eta_0 settled on our 03/25 meeting was 4.1e-8V^2/GHz which when integrated across 40GHz translates <u>to 1.28mV</u> RMS (differential) in terms of a minimum instrument noise floor V-RMS = sqrt(4.1e-8V^2/GHz * 40GHz)=1.28e-3V RMS



C2M VEC with Rx Noise: Yasuo Hidaka, Phil Sun: Credo

http://www.ieee802.org/3/ck/public/adhoc/feb19_20/hidaka_3ck_adhoc_01_021920.pdf

Simulation Conditions

- ✤ 405 test cases for each condition
- 27 IEEE802.3ck C2M channels (same as base channel set in <u>sun_3ck_01a_0120</u>)
- 15 cases of Tx PKG zp ([12:20 22:2:32] mm)
- 1 case of Rx PKG zp (0mm for TP1a, 6mm for whole link)
- COM parameters (details in back up slides)
- Same as <u>sun_3ck_02_1119</u> (slides 19,20) except eta_0 and b_{max}(1)
- COM 2.76

_								
	Ту	ре	TP1a			Whole Link		
ī.	Condition Label		TPx1	TD _V 5	TPx10	WLx1	WLx5	WLx10
	eta_0 (V^2/GHz)		0.82E-8	4.1E-8	8.2E-8	0.82E-8	4.1E-8	8.2E-8
	Desult	VEC	VECx1	VECx5	VECx10			
	Result	EH	EHx1	EHx5	EHx10			
	Laber	COM				COMx1	COMx5	COMx10
	TX FIR		3 pre, 1 post optimized for each case			Coefficients fixed to the optimization result of TPxN for WLxN		
	CTLE		2 zero, 3 poles optimized for each case			2 zero, 3 poles optimized for each case		
	D	FE	4 tap (b _{max} (1)=0.3 or 0.5, b _{max} ([2-4])=0.2) optimized for each case			4 tap (b _{max} (1)=0.3 or 0.5, b _{max} ([2-4])=0.2) optimized for each case		

IEEE P802.3ck Task Force

IEEE 802.3ck

KEYSIGHT TECHNOLOGIES

For task force discussion.

CI 120G

Hidaka, Yasuo

Comment Type

SuggestedRemedy

Proposed Response

SC 120G.3.1

TR

Change Table 120G-1 as follows:

Change Table 120G-9 as follows:

Change Table 120G-1 as follows:

Change Table 120G-9 as follows:

PROPOSED ACCEPT IN PRINCIPLE.

at TP1a with Rx noise of eta 0 = 4.1E-8V^2/GHz.

Change the value of b max(1) from TBD to 0.5.

Change the value of b_max(2) from TBD to 0.15. Change the value of b_max(3) from TBD to 0.1.

Change the value of b max(4) from TBD to 0.05.

Change the value of b_max(1) from TBD to 0.3. Change the value of b_max(2) from TBD to 0.2. Change the value of b_max(3) from TBD to 0.1. Change the value of b_max(4) from TBD to 0.0.05

P 221

As we discussed in ad hoc in hidaka 3ck adhoc 01 021920, I recommend max 9dB VEC

Comment Status D

In the same presentation, EH (min) and bmax(n) were also provided.

Change the value of vertical eye closure (max) from TBD dB to 9 dB. Change the value of eye height, differential (min) from 15 mV to 14mV.

Change the value of eta 0 from TBD V^2/GHz to 4.1E-8V^2/GHz.

Change the value of vertical eye closure (max) from TBD dB to 9 dB. Change the value of eye height, differential (min) from 15 mV to 13.5mV.

Change the value of eta 0 from TBD V^2/GHz to 4.1E-8V^2/GHz.

Response Status W

Alternatively, if a lower value of b_max(1) is preferred, the following is also OK.

Credo Semiconductor

L 20

11

VEC/EH/BMAX

Eta_0 noise term expressed as RMS noise voltage



(EYSIGH1

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KEYSIGHT TECHNOLOGIES

Backup Content

Input Referred Noise Floor Instrument Considerations

N1060A Module Specifications



N1060A General Specifications

		Item	Optio	on 050	Option 085		
Bandwidtl	h ^a , 3 dB (us	er selectable)	50 GHz		50 GHz, 70 GHz, 85 GHz, and 95 GHz (characteristic)		
Risetime (10% to 90%, calculated from TR = 0.35/BW)					7 ps (charact	eristic)	4 ps (characteristic)
RMS noise							
Characteristic					0.7 mV (50 GHz)		0.7 mV (50 GHz) 1.1 mV (75 GHz) 1.2 mV (85 GHz) 1.6 mV (95 GHz)
Maximum					1 mV (50 GHz)		1 mV (50 GHz) 1.3 mV (75 GHz) 1.6 mV (85 GHz) 2.0 mV (95 GHz)
				e	14	*	
				8	22	*	

- Sampling noise (with CDR) on equivalent time instrumentation is ~.8mV. Differentially this would be sqrt(2) * .8mV = 1.13mVrms
- +0.14mVrms margin
- Note this is at 50GHz not 40GHz



Input Referred Noise Floor Instrument Considerations

RMS Noise Floor – 1.85 mm (40 GHz to 70 GHz models)	UXR0404A / UXR0402A	UXR0504A / UXR0502A
Vertical setting, Full scale		
60 mV _{full scale (fs)}	340 µV (rms)	410 µV (rms)
100 mVfull scale (fs)	490 µV (rms)	560 µV (rms)
160 mV _{full scale (fs)}	720 µV (rms)	820 µV (rms)
400 mV _{full scale (fs)}	1.6 mV (rms)	1.8 mV (rms)
800 mV _{full scale (fs)}	3.4 mV (rms)	3.7 mV (rms)
1.6 Vfull scale (fs)	6.7 mV (rms)	7.5 mV (rms)
4.0 Vfull scale (fs)	16 mV (rms)	18 mV (rms)

 Real-time instrumentation at 40GHz and a 400mV single ended signal operates at aproximatly1.8mV rms. Differential at 800mV would have an intrinsic noise floor of sqrt(2) * 1.8mV = 2.5mV rms.

